

 <p>U.S. Department of Commerce, Patent and Trademark Office</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(Use several sheets if necessary)</p>	Application No.:	10/731,991
	Filing Date:	December 9, 2003
	First Named Inventor:	Peter G. Borden
	Group Art Unit:	2858
	Examiner Name:	Unknown
	Confirmation No.:	5839
Attorney Docket No.:	00849402USA BX17-1D	

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
IA	1.	4,873,434	10/10/89	See et al.	250	235		
	2.	6,541,747 B1	4/1/03	Kikuchi et al.	250	201		
	3.	2002/0167326 A1	11/14/02	Borden et al.	324	752		
	4.	2002/0105636 A1	8/8/02	Okawauchi	356	237		
	5.	5,530,550	6/25/96	Nikoonahad et al.	356	375		
	6.	5,610,718	3/11/97	Sentoku et al.	356	363		
	7.	4,758,092	7/19/88	Heinrich et al.	356	364		
	8.	6,411,389	6/25/02	Rushford	356	492		
IA	9.	6,072,179	6/6/00	Paniccia et al.	250	341		
Foreign Patent Documents								
		Document	Date	Country	Class	Subclass	Translation	
							Yes	No
IA	10.	0 566 217 A3	<del>0 566 217 A3</del> 12/93	EP	G01B	11/06	X	
	11.	3158766	<del>3158766</del> 7/91	JP	G01R	19/00	X	
	12.	0 313 681	<del>0 313 681</del> 5/89	EP	G03F	9/00	X	
	13.	02102404	<del>2102404</del> 4/90	JP	G01B	11/24	X	
IA	14.	2000021748	<del>2000021748</del> 1/00	JP	H01L	21/027	X	
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
IA	15.	H.K. Heinrich et al., "Picosecond Backside Optical Detection of Internal Signals in Flip-Chip Mounted Silicon VLSI Circuits", Microelectronic Engineering 16 (1992) March, pp 313-324						
	16.	Chung Wah See and Mehdi Vaez-Iravani, "Differential amplitude scanning optical microscope: theory and applications", Applied Optics Vol. 27, No. 13, July 1, 1988, pp 2786-2792						
	17.	ISR PCT/US04/040969, International filing date 08/12/04						
	18.	PCT/US04/040969 Written Opinion, International filing date 08/12/04						
	19.	ISR PCT/US04/041256, International filing date 08/12/04						
IA	20.	PCT/US04/041256 Written Opinion, International filing date 08/12/04						

Examiner:	/Isiaka Akanbi/	Date Considered:	05/11/2006
<p>* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.</p>			